

## 74LVTN16374 3.3V, 16-Bit D-Type Edge-Triggered Flip-Flop with 3-State Outputs

## GENERAL DESCRIPTION

The 74LVTN16374 is 16-bit D-type edge-triggered flip-flop with non-inverting 3-state outputs which is designed 3.3V supply voltage. The device can provide capability in driving highly capacitive or relatively low-impedance loads. That makes it especially suitable for use in implementing buffer registers, I/O ports, bidirectional bus drivers and working registers.

The device is capable of using as two 8-bit flip-flops or one 16-bit flip-flop. For flip-flop, when the clock input nCP is on the positive transition, the nQn outputs will follow logic levels of the nDn inputs.

An output enable  $(n\overline{OE})$  input can make the eight outputs set to either high/low logic levels or high-impedance state.

nOE has no effect on built-in function of the flip-flop. When all outputs are in the high-impedance state, old data can be reserved or new data can be entered.

## **FEATURES**

- Wide Operating Voltage Range: 3.3V
- Input and Output Interface Capability to 5V System Environment
- +64mA/-32mA Output Current
- 16-Bit Edge-Triggered Flip-Flop
- 3-State Buffers
- Input and Output Switching Levels of TTL
- Power-up Reset
- Power-up 3-State
- No Bus Current Loading when Output is Connected to 5V Bus
- -40°C to +125°C Operating Temperature Range
- Available in a Green TSSOP-48 Package

## PACKAGE/ORDERING INFORMATION

MODEL	PACKAGE DESCRIPTION	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION
74LVTN16374	TSSOP-48	-40°C to +125°C	74LVTN16374XTS48G/TR	74LVTN16374 XTS48 XXXXX	Tape and Reel, 2500

#### MARKING INFORMATION

NOTE: XXXXX = Date Code, Trace Code and Vendor Code.



Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

## ABSOLUTE MAXIMUM RATINGS (1)

Supply Voltage, $V_{\text{CC}}$ 0.5V to 4.6V
Input Voltage, V <sub>I</sub> <sup>(2)</sup> 0.5V to 7V
Output Voltage, V <sub>O</sub> <sup>(2)</sup>
High-Impedance State0.5V to 7V
High-State or Low-State0.5V to MIN (7V, V <sub>CC</sub> + 0.5V)
Input Clamping Current, $I_{IK}(V_I < 0V)$ 50mA
Output Clamping Current, $I_{OK}(V_O < 0V)$ 50mA
Output Current, I <sub>O</sub>
High-State64mA
Low-State128mA
Supply Current, I <sub>CC</sub> 128mA
Ground Current, I <sub>GND</sub> 256mA
Junction Temperature (3)+150°C
Storage Temperature Range65°C to +150°C
Lead Temperature (Soldering, 10s)+260°C
ESD Susceptibility
HBM7000V
CDM1000V

#### RECOMMENDED OPERATING CONDITIONS

Supply Voltage, V <sub>CC</sub>	2.7V to 3.6V
Input Voltage, V <sub>I</sub>	0V to 5.5V
Output Voltage, Vo	
High-Impedance State	0V to 5.5V
High-State or Low-State	0V to V <sub>CC</sub>
High-Level Output Current, I <sub>OH</sub>	32mA
Low-Level Output Current, I <sub>OL</sub>	64mA
Input Transition Rise and Fall Rate, Δt/Δ\	V
	10ns/V (MAX)
Operating Temperature Range	40°C to +125°C

### **OVERSTRESS CAUTION**

- 1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.
- 2. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.
- 3. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

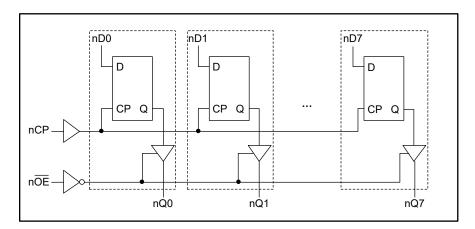
#### **ESD SENSITIVITY CAUTION**

This integrated circuit can be damaged if ESD protections are not considered carefully. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because even small parametric changes could cause the device not to meet the published specifications.

#### **DISCLAIMER**

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

## **LOGIC DIAGRAM**



## **FUNCTION TABLE**

OPERATING MODE	со	NTROL INP	TUT	INTERNAL	OUTPUT
OFERATING MODE	nŌĒ	nCP	nDn	REGISTER	nQn
Lood and Boad Bogistor	L	1	I	L	L
Load and Read Register	L	1	h	Н	Н
Hold	L	NC	X	NC	NC
Disable Outputs	Н	NC	Х	NC	Z
Disable Outputs	Н	<b>↑</b>	nDn	nDn	Z

H = High Voltage Level

L = Low Voltage Level

↑ = Low-to-High Clock Transition

h = High Voltage Level One Set-Up Time Prior to the Low-to-High Clock Transition

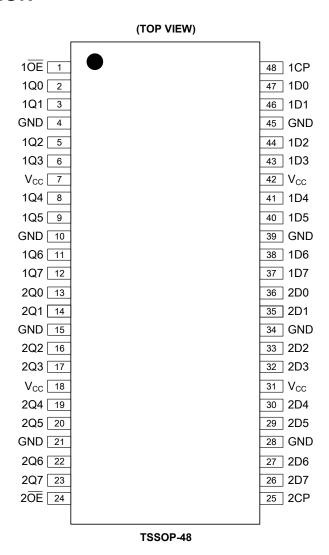
I = Low Voltage Level One Set-Up Time Prior to Low-to-High Clock Transition

Z = High-Impedance State

NC = No Change

X = Don't Care

## **PIN CONFIGURATION**



## **PIN DESCRIPTION**

PIN	NAME	FUNCTION
47, 46, 44, 43, 41, 40, 38, 37	1D0, 1D1, 1D2, 1D3, 1D4, 1D5, 1D6, 1D7	Data Inputs.
36, 35, 33, 32, 30, 29, 27, 26	2D0, 2D1, 2D2, 2D3, 2D4, 2D5, 2D6, 2D7	Data Inputs.
1, 24	1 <del>0E</del> , 2 <del>0E</del>	Output Enable Inputs (Active Low).
48, 25	1CP, 2CP	Clock Inputs.
2, 3, 5, 6, 8, 9, 11, 12	1Q0, 1Q1, 1Q2, 1Q3, 1Q4, 1Q5, 1Q6, 1Q7	Data Outputs.
13, 14, 16, 17, 19, 20, 22, 23	2Q0, 2Q1, 2Q2, 2Q3, 2Q4, 2Q5, 2Q6, 2Q7	Data Outputs.
4, 10, 15, 21, 28, 34, 39, 45	GND	Ground.
7, 18, 31, 42	V <sub>CC</sub>	Supply Voltage.

## **ELECTRICAL CHARACTERISTICS**

(Full = -40°C to +125°C, all typical values are measured at  $V_{CC}$  = 3.3V and  $T_A$  = +25°C, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITI	IONS	TEMP	MIN	TYP	MAX	UNITS	
Input Clamping Voltage	V <sub>IK</sub>	V <sub>CC</sub> = 2.7V, I <sub>IK</sub> = -18mA		Full	-1.2	-0.78		V	
High-Level Input Voltage	V <sub>IH</sub>	V <sub>CC</sub> = 2.7V to 3.6V		Full	2			V	
Low-Level Input Voltage	V <sub>IL</sub>	V <sub>CC</sub> = 2.7V to 3.6V		Full			8.0	V	
		$I_{OH} = -100 \mu A$ , $V_{CC} = 2.7 V to$	o 3.6V	Full	V <sub>CC</sub> - 0.05	V <sub>CC</sub> - 0.001			
High-Level Output Voltage	V <sub>OH</sub>	I <sub>OH</sub> = -8mA, V <sub>CC</sub> = 2.7V		Full	2.45	2.6		V	
		I <sub>OH</sub> = -32mA, V <sub>CC</sub> = 3.0V		Full	2.1	2.65			
		V - 0.7V	I <sub>OL</sub> = 100μA	Full		0.001	0.05		
		V <sub>CC</sub> = 2.7V	I <sub>OL</sub> = 24mA	Full		0.15	0.28		
Low-Level Output Voltage	V <sub>OL</sub>		I <sub>OL</sub> = 16mA	Full		0.1	0.18	V	
		V <sub>CC</sub> = 3.0V	I <sub>OL</sub> = 32mA	Full		0.2	0.36	1	
			I <sub>OL</sub> = 64mA	Full		0.4	0.55	1	
Power-Up Low-Level Output Voltage (1)	V <sub>OL_PU</sub>	V <sub>CC</sub> = 3.6V, I <sub>OL</sub> = 1mA, V <sub>I</sub> =	Full		5	50	mV		
	I	Control pins, V <sub>CC</sub> = 3.6V, V <sub>I</sub> = V <sub>CC</sub> or GND		Full		±0.01	±1		
		Control pins, V <sub>CC</sub> = 0V or 3	Full		0.01	5			
Input Leakage Current		Input data pins (2), V <sub>CC</sub> = 0\	Full		0.01	5	μΑ		
		Input data pins (2), V <sub>CC</sub> = 3.6V, V <sub>I</sub> = V <sub>CC</sub>		Full		0.01		1	
		Input data pins <sup>(2)</sup> , V <sub>CC</sub> = 3.6V, V <sub>I</sub> = GND		Full	-2	-0.01		1	
25.01			V <sub>O</sub> = 3.0V	Full		0.01	2		
Off-State Output Current	l <sub>oz</sub>	V <sub>CC</sub> = 3.6V	V <sub>O</sub> = 0.5V	Full	-2	-0.01		μA	
Output Leakage Current	I <sub>LO</sub>	Output in high-state when $V_0 = 5.5V$ , $V_{CC} = 3.0V$		Full		1	30	μA	
Power-Up/Down Output Current	I <sub>O_PU/PD</sub>	$V_{CC} \le 1.2V$ , $V_{O} = 0.5V$ to $V_{O} = 0.5V$ to $V_{O} = 0.5V$ to $V_{O} = 0.5V$	$V_{CC}$ , $V_I = GND$ or $V_{CC}$ ,	+25°C		0.01	10	μΑ	
Power-Off Leakage Current	I <sub>OFF</sub>	$V_{CC} = 0V$ , $V_1$ or $V_0 = 0V$ to	5.5V	Full		0.01	10	μA	
		V <sub>CC</sub> = 3.6V,	Outputs high	Full		12	80		
Supply Current	I <sub>CC</sub>	$V_I = GND \text{ or } V_{CC},$	Outputs low	Full		12	80	μΑ	
		I <sub>O</sub> = 0A	Outputs disabled (3)	Full		12	80	1	
Additional Supply Current (4)	$\Delta I_{CC}$	Per input pin, $V_{CC} = 3.0V$ to 3.6V, one input at $V_{CC} = 0.6V$ , other inputs at $V_{CC} = 0.6V$		Full		0.2	80	μA	
Input Capacitance	Cı	Input pins, V <sub>I</sub> = 0V or 3.0V		+25℃		6		pF	
Output Capacitance	Co	Output pins nQn, outputs o $V_0 = 0V$ or $V_{CC}$	disabled,	+25°C		9		pF	

#### NOTES:

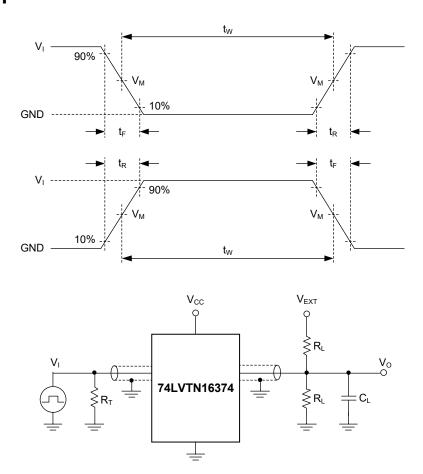
- 1. For valid test results, data must not be loaded into the flips-flops (or latches) after applying power.
- 2. Unused pins at  $V_{\text{CC}}$  or GND.
- 3.  $I_{\text{CC}}$  is measured with outputs pulled to  $V_{\text{CC}}$  or GND.
- 4. This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND.

## **DYNAMIC CHARACTERISTICS**

(For test circuit, see Figure 1. All typical values are measured at  $V_{CC}$  = 3.3V and  $T_A$  = +25°C, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS			MIN	TYP	MAX	UNITS	
Maximum Frequency	f <sub>MAX</sub>	nCP, $V_{CC} = 3.3V \pm 0.3V$ , se	e Figure 2	+25°C		150		MHz	
Low to High Propagation Delay	+	nCP to nQn, see Figure 2	$V_{CC} = 3.3V \pm 0.3V$	+25°C		3.4		no	
Low to high Propagation Delay	t <sub>PLH</sub>	nor to fight, see Figure 2	V <sub>CC</sub> = 2.7V	+25°C		3.9		ns	
High to Low Propagation Delay	t <sub>PHL</sub>	nCP to nQn, see Figure 2	$V_{CC} = 3.3V \pm 0.3V$	+25°C		3.3		ns	
Trigit to Low Propagation Delay	PHL	nor to fight, see rigule 2	V <sub>CC</sub> = 2.7V	+25°C		3.5		115	
Off-State to High Propagation Delay	$t_{PZH}$	nOE to nQn, see Figure 3	$V_{CC} = 3.3V \pm 0.3V$	+25°C		4.3		ne	
On-State to High Propagation Delay	чРZН	noe to non, see rigule 3	V <sub>CC</sub> = 2.7V	+25°C		3.9		ns	
Off-State to Low Propagation	+	nOE to nOn ooo Figure 2	$V_{CC} = 3.3V \pm 0.3V$	+25°C		4.4		ne	
Delay	$t_{PZL}$	nOE to nQn, see Figure 3	V <sub>CC</sub> = 2.7V	+25°C		4.3		ns	
Llink to Off Ctata Duananation Delay		nOE to nQn, see Figure 3	$V_{CC} = 3.3V \pm 0.3V$	+25°C		4.5		no	
High to Off-State Propagation Delay	$t_{PHZ}$		V <sub>CC</sub> = 2.7V	+25°C		4		ns	
Low to Off-State Propagation	t <sub>PLZ</sub>		$V_{CC} = 3.3V \pm 0.3V$	+25°C		3.8		ns	
Delay	<b>L</b> PLZ	nOE to nQn, see Figure 3	V <sub>CC</sub> = 2.7V	+25°C		3.4		115	
Set-Up Time	4	nDn to nCP, high or low,	$V_{CC} = 3.3V \pm 0.3V$	+25°C		0.3		no	
Set-op Time	t <sub>su</sub>	see Figure 4	V <sub>CC</sub> = 2.7V	+25°C		0.3		ns	
Hold Time	+	nDn to nCP, high or low,	$V_{CC} = 3.3V \pm 0.3V$	+25°C		0.2		no	
Inoid Time	t <sub>H</sub>	see Figure 4	V <sub>CC</sub> = 2.7V	+25°C		0.2		ns	
		nCD high, and Figure 2	$V_{CC} = 3.3V \pm 0.3V$	+25°C		1.5			
Distant Maria		nCP high, see Figure 2	V <sub>CC</sub> = 2.7V	+25°C	_	1.5		]	
Pulse Width	t <sub>W</sub>	nCD low ood Figure 2	$V_{CC} = 3.3V \pm 0.3V$	+25°C		1.5		ns	
		nCP low, see Figure 2	V <sub>CC</sub> = 2.7V	+25°C		1.5			

## **TEST CIRCUIT**



Test conditions are given in Table 1.

Definitions for test circuit:

R<sub>L</sub>: Load resistance.

C<sub>L</sub>: Load capacitance (includes jig and probe).

 $R_T$ : Termination resistance (equals to output impedance  $Z_0$  of the pulse generator).

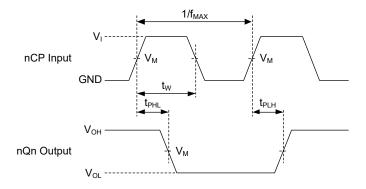
 $\ensuremath{V_{\text{EXT}}}\xspace$  : External voltage used to measure switching time.

Figure 1. Test Circuit for Measuring Switching Times

**Table 1. Test Conditions** 

SUPPLY VOLTAGE		INP	UT		LO	LOAD V <sub>EXT</sub>			
V <sub>cc</sub>	Vı	fi	t <sub>W</sub>	t <sub>R</sub> , t <sub>F</sub>	CL	$R_L$	t <sub>PHZ</sub> , t <sub>PZH</sub>	t <sub>PLZ</sub> , t <sub>PZL</sub>	t <sub>PLH</sub> , t <sub>PHL</sub>
2.7V to 3.6V	2.7V	≤ 10MHz	500ns	≤ 2.5ns	50pF	500Ω	GND	6V	Open

## **WAVEFORMS**

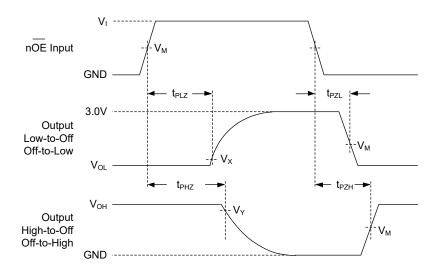


Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical output voltage levels that occur with the output load.

Figure 2. Clock Input to Output Propagation Delays, Clock Pulse Width and Maximum Clock Frequency



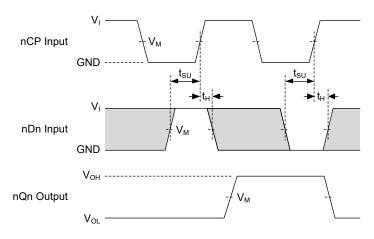
Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels:  $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical output voltage levels that occur with the output load.

Figure 3. Enable and Disable Times

## **WAVEFORMS** (continued)



Test conditions are given in Table 1.

Measurement points are given in Table 2.

Logic levels: V<sub>OL</sub> and V<sub>OH</sub> are typical output voltage levels that occur with the output load.

The shaded areas indicate when the input is permitted to change for predictable output performance.

Figure 4. Data Set-Up and Hold Times

**Table 2. Measurement Points** 

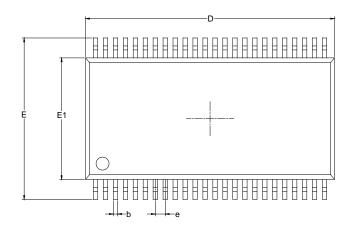
SUPPLY VOLTAGE	INF	TUT	OUTPUT				
V <sub>cc</sub>	V <sub>I</sub> V <sub>M</sub>		V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>		
2.7V to 3.6V	2.7V	1.5V	1.5V	V <sub>OL</sub> + 0.3V	V <sub>OH</sub> - 0.3V		

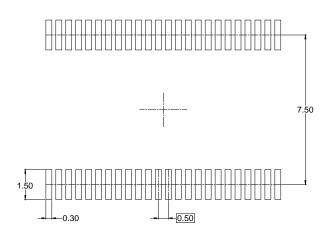
## **REVISION HISTORY**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

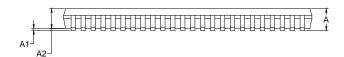
NOVEMBER 2021 – REV.A to REV.A.1	Page
Updated HBM value in Absolute Maximum Ratings section	2
Changes from Original (MARCH 2021) to REV.A	Page
Changed from product preview to production data	All

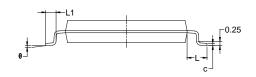
# **PACKAGE OUTLINE DIMENSIONS** TSSOP-48





RECOMMENDED LAND PATTERN (Unit: mm)





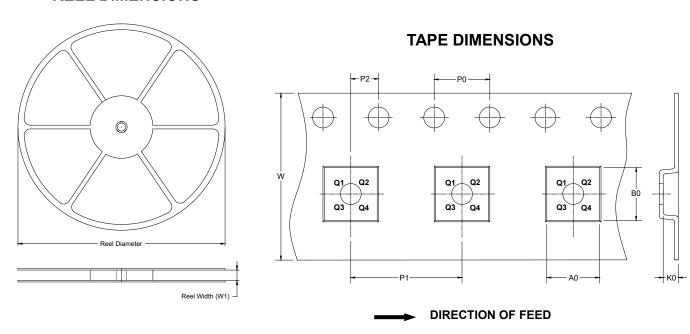
Cymhal	Dir	mensions In Millimet	ers
Symbol	MIN	MOD	MAX
А			1.20
A1	0.05	0.10	0.15
A2	0.85	0.95	1.05
b	0.18	0.18	
С	0.15		0.19
D	12.40	12.50	12.60
Е	7.90	8.10	8.30
E1	6.00	6.10	6.20
е		0.50 BSC	
L		1.00 REF	
L1	0.45		0.75
θ	0°		8°

- NOTES:

  1. Body dimensions do not include mode flash or protrusion.
- 2. This drawing is subject to change without notice.

## TAPE AND REEL INFORMATION

## **REEL DIMENSIONS**

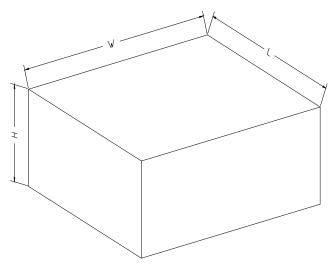


NOTE: The picture is only for reference. Please make the object as the standard.

## **KEY PARAMETER LIST OF TAPE AND REEL**

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TSSOP-48	13"	24.4	8.60	13.00	1.80	4.0	12.0	2.0	24.0	Q1

## **CARTON BOX DIMENSIONS**



NOTE: The picture is only for reference. Please make the object as the standard.

## **KEY PARAMETER LIST OF CARTON BOX**

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
13"	386	280	370	5